The Nanotechnology Solutions Partner

www.parkAFM.com

Workshop on Atomic Force Microscope and Nanotechnology
(Attendance is free with RSVP)

Park Systems is pleased to invite you to a workshop on AFM applications in nanotechnology
and demonstration of the award-winning XE-70 AFM.
The agenda for each workshop includes:

10:00 – 10:15	Introduction
10:15 – 11:00	"Overview of the XE-series AFM/SPM R&D instrumentation"
11:00 – 11:45	"Advanced applications utilizing the ancillary modes of the XE-series AFM/SPM R&D instrumentation"
11:45 – 12:45	Complimentary Lunch
12:45 – 14:30	Demonstration

Workshops will be held at the following locations:

Wednesday, September 24, 2008
Cerium Labs. (all visitors welcome)
5204 E. Ben White Blvd., Bldg 1, Austin, TX 78741
10am – 2:30pm

Thursday, September 25, 2008
Nanotechnology Center, Univ. of Texas, Bldg NST
102 E. 24th St., Austin, TX 78712
Room 1.104
10am – 2:30pm

Friday, September 26, 2008
Location TBD depending on demand
Dallas or Houston
10am – 2:30pm

Please RSVP to Park Systems at 408-986-1110 or at sathya@parkafm.com. Be sure to bring samples (to be imaged later at our Application Labs.).

Park Systems Company Fact Sheet

Park SYSTEMS www.parkAFM.com

For more information: info@parkAFM.com www.parkAFM.com

Nanotechnology Solutions Partner

Park Systems is the nanotechnology solutions partner for the most demanding imaging and measurement needs in research and industry. The company serves the customers with optimized metrology solutions in nanoscale including atomic force metrology tools, software, and global service and support.

25-Year History in AFMs

The root of Park Systems can be found at Stanford University, the birthplace of atomic force microscope; Drs. Sang-il Park (Chairman and CEO) and Sung Park (General Manager of US Operations), original founders of Park Scientific Instruments, were applied physics graduates at the University and developed the world-fist commercial AFM in 1989. The spin-off company (PSIA) was renamed Park Systems in 2007. Following continuous growth over 20 years, Park Systems currently has over 400 customers across the world in industry and research.

Evolution of Commercial AFM Technology Driven by Park Systems

Advantages of XE Technology

The award-winning XE-platform, completely eliminates background scanner curvature and shows no bowing even on scans of the flattest samples, thus enabling precision nanometrology for even the most challenging problems in industry and research.

Park Systems Clients

Park Systems' unique strength to deliver customized solutions by forming successful partnership with clients have been acknowledged by world leaders in industry including Seagate, Hitach, LG and Samsung. Our research products line has well- established reputation among world-class universities and research institutes including Harvard, Stanford and NASA.

Park Systems Company Fact Sheet

www.parkAFM.com

For more information: info@parkAFM.com www.parkAFM.com

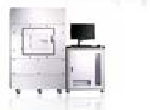
Nanotechnology Solutions Partner

Park Systems Worldwide

The Company has three overseas offices in the U.S., Japan, and Singapore and currently, **Park Systems** has developed global sales network over 21 countries.

Park Systems Product Line

XE-3DM
For Undercut and Sidewall Metrology



XE-CMP
For High Aspect Ratio Trench and CMP Metrology

XE-HDM
For General Hard Disk Media and Substrate Inspection and Metrology

XE-LCD
For Automated LCD Production Inspection and Metrology

XE-PTR
For In-line Pole Tip Recession Metrology of Hard Disk Sliders

XE-WAFER
For Wafer-based Inspection and Metrology

XE-70
Affordable, Research-Grade AFM with Flexible Sample Handling

XE-100
Versatile, Research-Grade AFM with Motorized Optics

XE-150
Premier Cross-Functional AFM with Motorized Sample Stage

XE-200
Enlarged Capacity Cross-Functional AFM with Motorized Sample Stage

XE-Bio
Bio Research in Nanoscale: In-liquid imaging and much more

XE-NSOM
For NSOM or Raman-AFM measurements

Park Systems. Inc. 3040 Olcott St. Santa Clara, CA 95054 Tel. +1-408-986-1110